

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10701167	CHAULK ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	CHAU NGUYEN	2176

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
715	200	02/14/2008	cn
715	212	02/14/2008	cn
715	213	02/14/2008	cn
715	214	02/14/2008	cn
715	220	02/14/2008	cn
715	229	02/14/2008	cn
715	238	02/14/2008	cn
715	242	02/14/2008	cn
715	252	02/14/2008	cn
715	255	02/14/2008	cn
707	1	02/14/2008	cn
707	7	02/14/2008	cn
707	200	02/14/2008	cn

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Updated Search on East Reports	02/13/2008	cn
	02/14/2008	cn
Interference Search on PGPUB	02/14/2008	cn
NPL Search on IEEE Database	02/14/2008	cn
Inventor Search for Double Patenting	02/14/2008	cn

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
715	200	02/14/2008	cn
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707	200	02/14/2008	